



RADIATION HARDENED NPN SILICON SWITCHING TRANSISTOR

Qualified per MIL-PRF-19500/366

Qualified Levels:
JANSM, JANSD,
JANSP, JANSL, and
JANSR

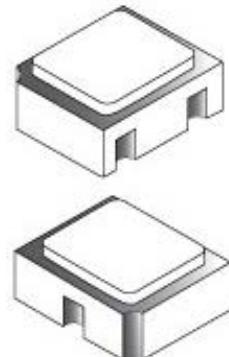
DESCRIPTION

This family of JANS 2N3501, epitaxial, planar transistors are military qualified in five RHA (Radiation Hardness Assurance) levels for high-reliability applications. These devices are also available in TO-5 and low profile TO-39 packaging. Microsemi also offers numerous other transistor products to meet higher and lower power ratings with various switching speed requirements in both through-hole and surface-mount packages.

Important: For the latest information, visit our website <http://www.microsemi.com>.

FEATURES

- Surface mount equivalent of JEDEC registered 2N3501 number.
- RHA level JAN qualifications per MIL-PRF-19500/366 (see [part nomenclature](#) for all options).
- RoHS compliant by design.



UB Package

APPLICATIONS / BENEFITS

- General purpose transistors for medium power applications requiring high frequency switching.
- Low profile ceramic package.
- Lightweight.
- Military and other high-reliability applications.

Also available in:

TO-5 package
(long-leaded)
2N3498L – 2N3501L

TO-39 (TO-205AD) package
(leaded)
2N3498 – 2N3501

MAXIMUM RATINGS @ $T_C = +25^\circ\text{C}$ unless otherwise noted

Parameters / Test Conditions	Symbol	Value	Unit
Collector-Emitter Voltage	V_{CEO}	150	V
Collector-Base Voltage	V_{CBO}	150	V
Emitter-Base Voltage	V_{EBO}	6.0	V
Collector Current	I_C	300	mA
Thermal Resistance Junction-to-Ambient	R_{EJA}	325	$^\circ\text{C}/\text{W}$
Total Power Dissipation @ $T_A = +25^\circ\text{C}$ ⁽¹⁾ @ $T_{SP} = +25^\circ\text{C}$ ⁽²⁾	P_T	0.5 1.5	W
Operating & Storage Junction Temperature Range	T_J, T_{stg}	-65 to +200	$^\circ\text{C}$

- Notes:**
1. See [figure 1](#).
 2. See [figure 2](#).

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MECHANICAL and PACKAGING

- CASE: Ceramic.
- TERMINALS: Gold plating over nickel under plate.
- MARKING: Part number, date code, manufacturer's ID.
- TAPE & REEL option: Standard per EIA-418D. Consult factory for quantities.
- WEIGHT: < 0.04 Grams.
- See [Package Dimensions](#) on last page.

PART NOMENCLATURE

JANSM 2N3501 UB

Reliability Level

JANSM = 3K Rads (Si)
 JANSD = 10K Rads (Si)
 JANSP = 30K Rads (Si)
 JANSL = 50K Rads (Si)
 JANSR = 100K Rads (Si)

Surface Mount package

JEDEC type number

SYMBOLS & DEFINITIONS

Symbol	Definition
C_{obo}	Common-base open-circuit output capacitance
I_{CEO}	Collector cutoff current, base open
I_{CEX}	Collector cutoff current, circuit between base and emitter
I_{EBO}	Emitter cutoff current, collector open
h_{FE}	Common-emitter static forward current transfer ratio
V_{CEO}	Collector-emitter voltage, base open
V_{CBO}	Collector-emitter voltage, emitter open
V_{EBO}	Emitter-base voltage, collector open

ELECTRICAL CHARACTERISTICS @ $T_A = +25^\circ\text{C}$, unless otherwise noted

Parameters / Test Conditions	Symbol	Min.	Max.	Unit
OFF CHARACTERISTICS				
Collector-Emitter Breakdown Voltage $I_C = 10 \text{ mA, pulsed}$	$V_{(\text{BR})\text{CEO}}$	150		V
Collector-Base Cutoff Current $V_{CB} = 75 \text{ V}$ $V_{CB} = 150 \text{ V}$	I_{CBO}		50 10	nA μA
Emitter-Base Cutoff Current $V_{EB} = 4.0 \text{ V}$ $V_{EB} = 6.0 \text{ V}$	I_{EBO}		25 10	nA μA

ON CHARACTERISTICS (1)

Forward-Current Transfer Ratio $I_C = 0.1 \text{ mA, } V_{CE} = 10 \text{ V}$ $I_C = 1.0 \text{ mA, } V_{CE} = 10 \text{ V}$ $I_C = 10 \text{ mA, } V_{CE} = 10 \text{ V}$ $I_C = 150 \text{ mA, } V_{CE} = 10 \text{ V}$ $I_C = 300 \text{ mA, } V_{CE} = 10 \text{ V}$	h_{FE}	35 50 75 100 20	300	
Collector-Emitter Saturation Voltage $I_C = 10 \text{ mA, } I_B = 1.0 \text{ mA}$ $I_C = 150 \text{ mA, } I_B = 15 \text{ mA}$	$V_{CE(\text{sat})}$		0.2 0.4	V
Base-Emitter Saturation Voltage $I_C = 10 \text{ mA, } I_B = 1.0 \text{ mA}$ $I_C = 150 \text{ mA, } I_B = 15 \text{ mA}$	$V_{BE(\text{sat})}$		0.8 1.2	V

DYNAMIC CHARACTERISTICS

Forward Current Transfer Ratio, Magnitude $I_C = 20 \text{ mA, } V_{CE} = 20 \text{ V, } f = 100 \text{ MHz}$	$ h_{fe} $	1.5	8.0	
Output Capacitance $V_{CB} = 10 \text{ V, } I_E = 0,$ $100 \text{ kHz} \leq f \leq 1.0 \text{ MHz}$	C_{obo}		8.0	pF
Input Capacitance $V_{EB} = 0.5 \text{ V, } I_C = 0, 100 \text{ kHz} \leq f \leq 1.0 \text{ MHz}$	C_{ibo}		80	pF

(1) Pulse Test: pulse width = 300 μs , duty cycle $\leq 2.0\%$.

ELECTRICAL CHARACTERISTICS @ $T_A = +25^\circ\text{C}$, unless otherwise noted (continued)
SWITCHING CHARACTERISTICS

Parameters / Test Conditions	Symbol	Min.	Max.	Unit
Turn-On Time $V_{EB} = 5 \text{ V}$; $I_C = 150 \text{ mA}$; $I_{B1} = 15 \text{ mA}$	t_{on}		115	ns
Turn-Off Time $I_C = 150 \text{ mA}$; $I_{B1} = I_{B2} = 15 \text{ mA}$	t_{off}		1150	ns

SAFE OPERATING AREA (See SOA figure and reference [MIL-STD-750 method 3053](#))
DC Tests

$T_C = +25^\circ\text{C}$, $t_r \geq 10 \text{ ns}$; 1 Cycle, $t = 1.0 \text{ s}$

Test 1

$V_{CE} = 10 \text{ V}$, $I_C = 113 \text{ mA}$

Test 2

$V_{CE} = 50 \text{ V}$, $I_C = 23 \text{ mA}$

Test 3

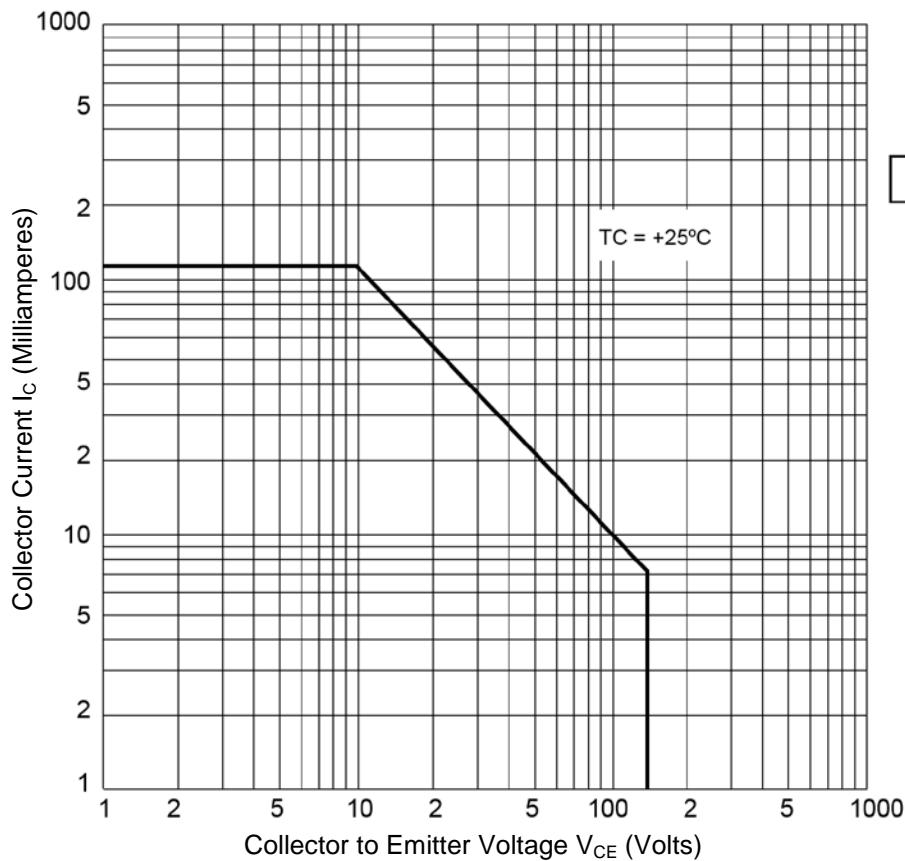
$V_{CE} = 80 \text{ V}$, $I_C = 14 \text{ mA}$

Clamped Switching

$T_A = +25^\circ\text{C}$

Test 1

$I_B = 50 \text{ mA}$, $I_C = 300 \text{ mA}$


Maximum Safe Operating Area

ELECTRICAL CHARACTERISTICS @ $T_A = +25^\circ\text{C}$, unless otherwise noted (continued)
POST RADIATION ELECTRICAL CHARACTERISTICS

Parameters / Test Conditions	Symbol	Min.	Max.	Unit
Collector-Emitter Breakdown Voltage $I_C = 10 \text{ mA}$	$V_{(\text{BR})\text{CEO}}$	150		V
Collector-Base Cutoff Current $V_{CB} = 150 \text{ V}$ $V_{CB} = 75 \text{ V}$	I_{CBO}		20 100	μA nA
Collector to Emitter Cutoff $V_{CE} = 120 \text{ V}$	I_{CEO}		2	μA
Emitter-Base Cutoff Current $V_{EB} = 4.0 \text{ V}$ $V_{EB} = 6.0 \text{ V}$	I_{EBO}		50 20	nA μA
Collector-Emitter Saturation Voltage $I_C = 10 \text{ mA}, I_B = 1.0 \text{ mA}$	$V_{CE(\text{sat})}$		0.23	V
Base-Emitter Saturation Voltage $I_B = 10 \text{ mA}, I_B = 1.0 \text{ mA}$ $I_B = 150 \text{ mA}, I_B = 15 \text{ mA}$	$V_{BE(\text{sat})}$		0.92 1.38	V

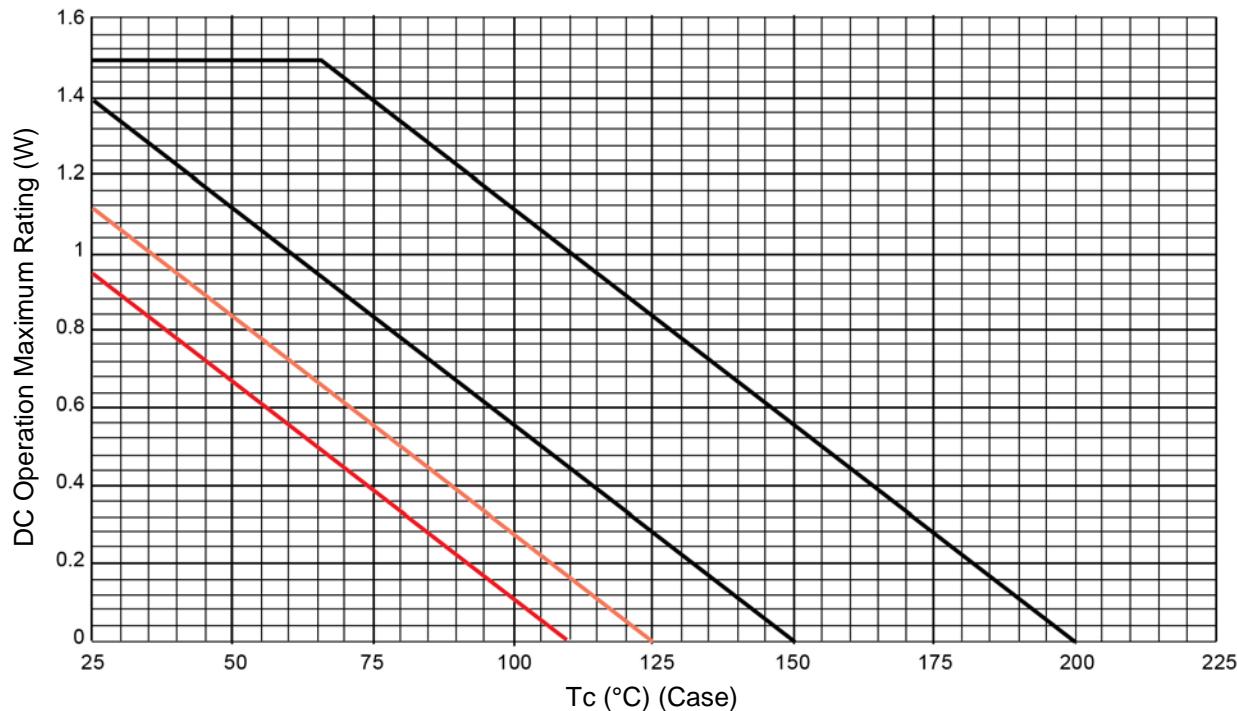
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FIGURE 1
Derating for all devices ($R_{\theta_{JSP}}$)

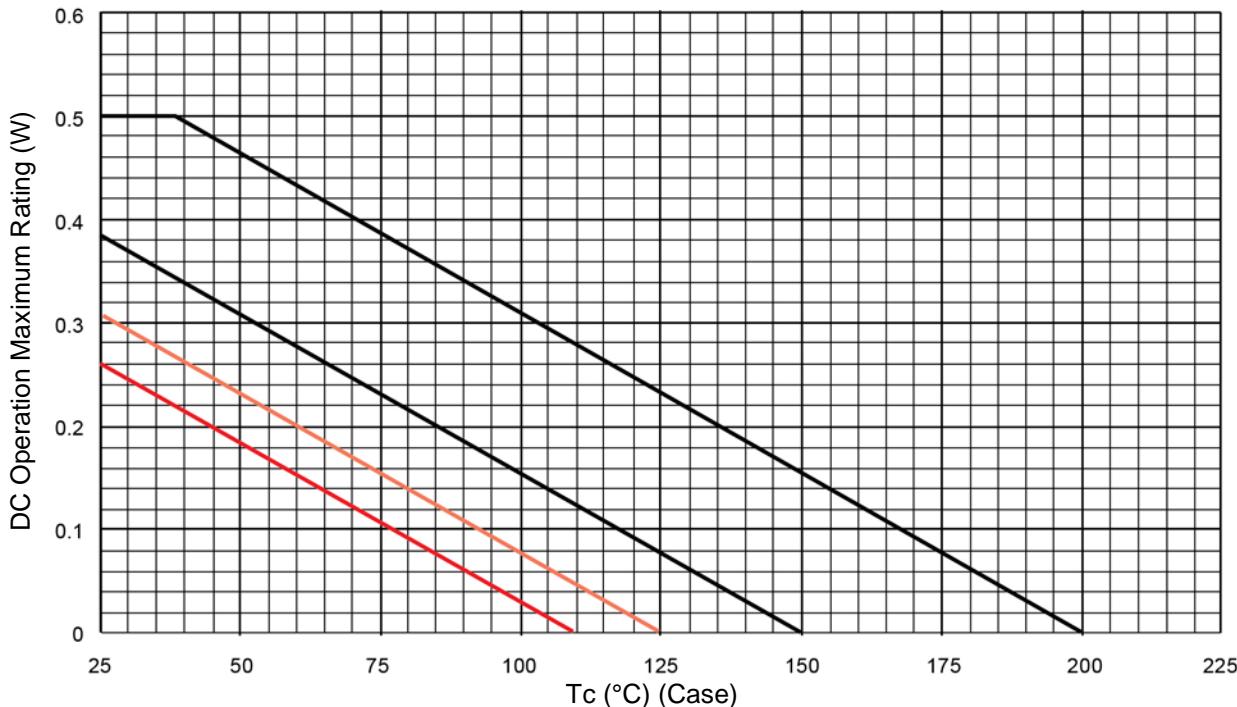


FIGURE 2
Derating for all devices ($R_{\theta_{JA}}$)

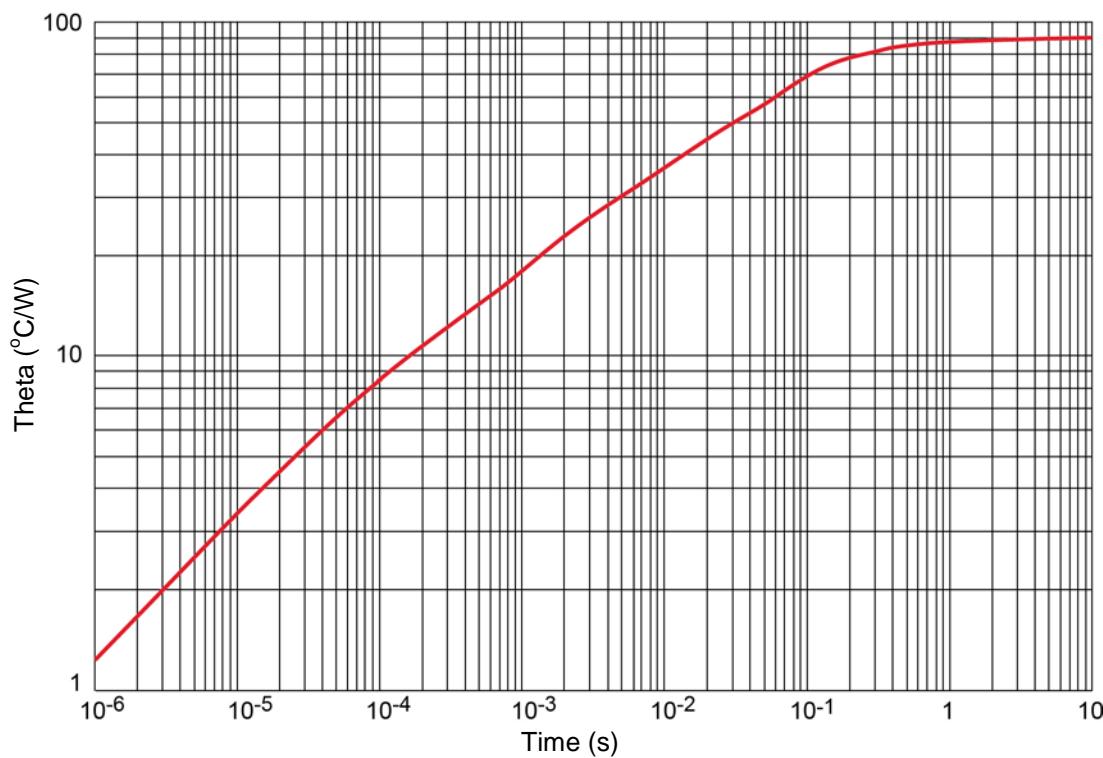
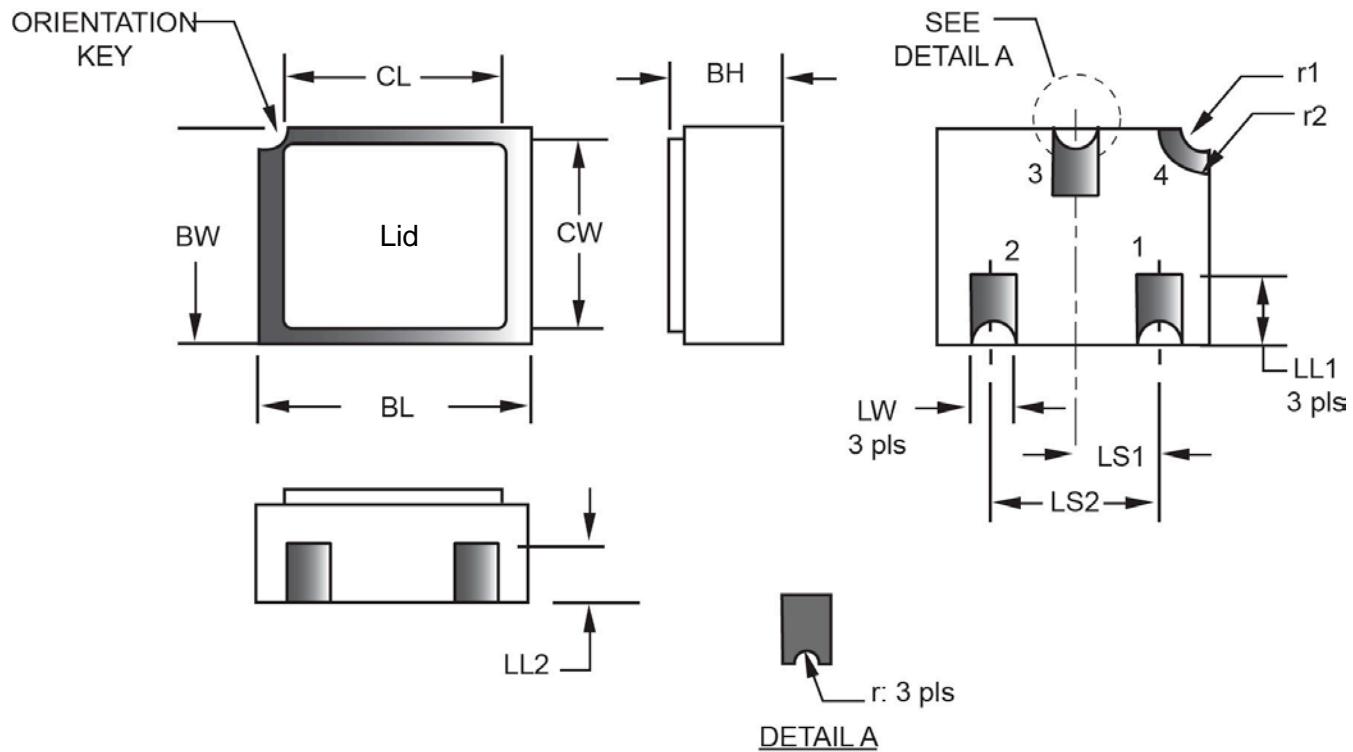
GRAPHS

FIGURE 3
Thermal impedance graph ($R_{\theta\text{JSP}}$)

PACKAGE DIMENSIONS


Symbol	Dimensions				Note	Symbol	Dimensions				Note			
	Inch		Millimeters				Inch		Millimeters					
	Min	Max	Min	Max			Min	Max	Min	Max				
BH	.046	.056	1.17	1.42		LS₁	.036	.040	0.91	1.02				
BL	.115	.128	2.92	3.25		LS₂	.071	.079	1.80	2.01				
BW	.085	.108	2.16	2.74		LW	.016	.024	0.41	0.61				
CL		.128		3.25		r		.008		0.20				
CW				2.74		r₁		.012		0.31				
LL₁	.022	.038	0.56	0.97		r₂		.022		0.56				
LL₂	.017	.035	0.43	0.89										

NOTES:

1. Dimensions are in inches.
2. Millimeters are given for general information only.
3. Hatched areas on package denote metallized areas.
4. Pad 1 = Base, Pad 2 = Emitter, Pad 3 = Collector, Pad 4 = Shielding connected to the lid.
5. In accordance with ASME Y14.5M, diameters are equivalent to Φx symbology.